

APPENDIX 3: Photographs of test setup

Conducted Emission

(Camera View + USB Communication + microSD card Access Mode)



Photo 1



Photo 2

UL Japan, Inc.

Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8999

Facsimile : +81 596 24 8124

Conducted Emission
(Charging + microSD card Access Mode)



Photo 1



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Radiated Emission
(Camera View + USB Communication + microSD card Access Mode)
Below 1GHz



Photo 1



Photo 2

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(Charging + microSD card Access Mode)
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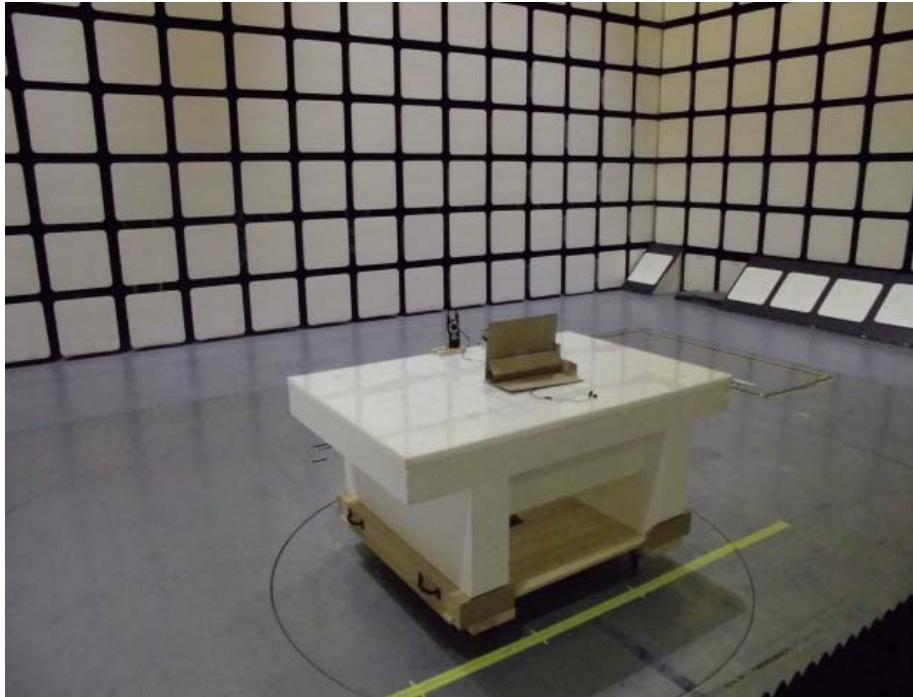


Photo 1

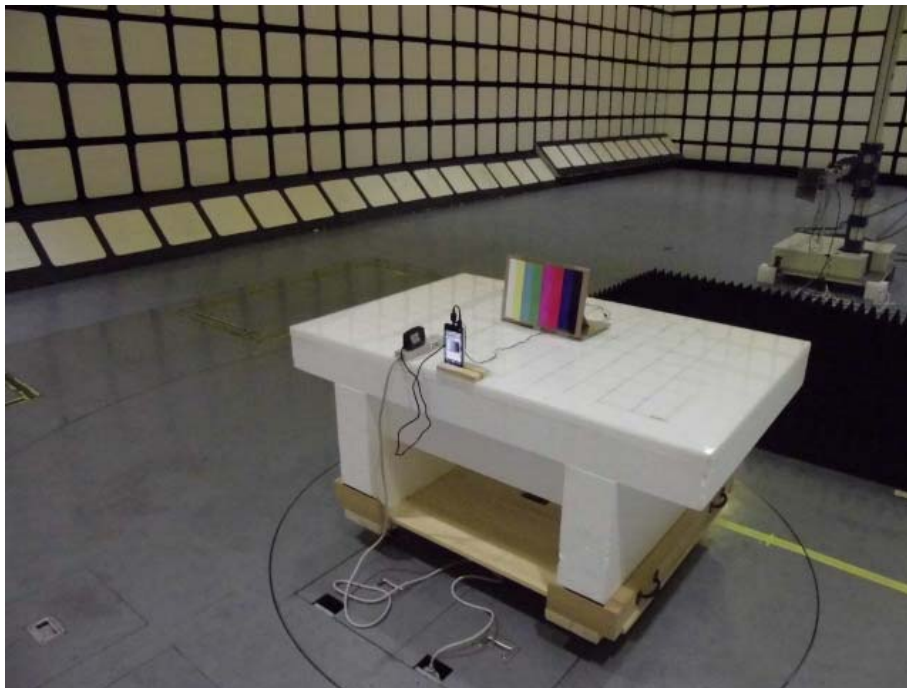


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Worst Case Position
(Horizontal: Z-axis/ Vertical:Z-axis)

X-axis



Y-axis



Z-axis



End of Report

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